Contents of Volume 6

NUMBER 1 JANUARY 1977

Editorial *1*

Quantitative X-Ray Diffraction Analysis by a Direct Calculation Method
D.H. HOOTON AND N.E. GIORGETTA *2*

Plant Analyses by X-Ray Spectrometry: I. Low Atomic Number elements, Sodium to Calcium
K. NORRISH AND J.T. HUTTON *6*

Plant Analyses by X-Ray Spectrometry: II. Elements of Atomic Number greater than 20
J.T. HUTTON AND K. NORRISH *12*

The Application of a 'Curve-fitting Computer Program' to compensate for Inter-element Effects in X-Ray Fluorescence Analysis of Rock Samples: The Determination of Vanadium in Geological Standards
CHRIS RIDDLE AND T.E. SMITH *18*

An Intercomparison of Trace Element Excitation Methods for Energy-dispersive Fluorescence Analyzers
D.A. GEDCKE, E. ELAD AND P.B. DENEE *21*

Hybride Röntgenfluoreszenzanalyse
J. KRAMER, H. EBEL AND F. TSCHIMAROV *30*

Processing of Energy-dispersive X-Ray Spectra
J.C. RUSS *37*

A Simplified Fundamental Parameters Method for Quantitative Energy-dispersive X-Ray Fluorescence Analysis
R.B. SHEN AND J.C. RUSS *56*

NUMBER 2 APRIL 1977

Editorial *63*

Fe $K\beta_{1,3}$ X-Ray Emission Spectra from Complexes which contain Ferric Ion in Unconventional Spin States
D.S. URCH AND S. WEBBER *64*

X-Ray Spectrometric Analysis of Trace Elements in Rocks. Correction for Instrumental Interferences
H. BOUGAULT, P. CAMBON AND H. TOULHOAT *66*

Improved Spatial Resolution Microanalysis in a Scanning Transmission Electron Microscope
R.G. FAULKNER, T.C. HOPKINS AND K. NORRGÅRD *73*

X-Ray Tube Excited Fluorescence Method Using Critical Absorbers
P. PUUMALAINEN *80*

The Loss of Br from Thin-Film Samples During X-Ray Fluorescence Analysis
B.H. O'CONNOR, G.C. KERRIGAN AND P. HINCHLIFFE *83*

X-Ray Spectrochemical Matrix Correction in the Analysis of Copper Ores
S.H. HALL AND L.E. HARBISON *86*

Some Comments on the Deterioration of Rubidium Acid Phthalate Analysing Crystals
S. FREGERSLEV *89*

X-Ray Production by 5.2–27 MeV Alpha Particles
T. BADICA, C. CIORTEA, S. DIMA, A. PETROVICI, I. POPESCU AND V. NEACŞU *90*

Pile-up Rejection: Limitations and Corrections for Residual Errors in Energy-dispersive Spectrometers
P.J. STATHAM *94*

Nomenclature in X-Ray Spectrometry *104*

Letter to the Editor *110*

CONTENTS OF VOLUME 6

NUMBER 3 JULY 1977

Editorial *111*

Mise au Point du Dosage du Brome dans le Plasma et la Sueur à l'aide d'un Spectromètre à Fluorescence X à Source Isotopique Annulaire de Cadmium 109
Y. BARBIER, E. PEHLIVANIAN ET C. GIRARD *112*

Accuracy of X-Ray Fluorescence Spectrometric Determination of Rb and Sr Concentrations in Rock Samples
E.A.TH. VERDURMEN *117*

Crossed Influence Coefficients for Accurate X-Ray Fluorescence Analysis of Multicomponent Systems
R. TERTIAN AND R. VIE LE SAGE *123*

The Absolute Determination of the Reflection Integral of Bragg X-Ray Analyser Crystals. Two-reflection Methods.
K.D. EVANS, BRYAN LEIGH AND MARGARET LEWIS *132*

Proton-induced X-Ray Production in Vanadium, Iron, Zinc, Gallium, Yttrium, Cadmium, Indium and Tin
MD. RASHIDUZZAMAN KHAN, A.G. HOPKINS, D. CRUMPTON AND P.E. FRANCOIS *140*

Rapid Increase of Sodium Count Rates During the Electron Microprobe Analysis of Sepiolite. The Role of Zeolitic Water
C.R.M. BUTT AND R.B.W. VIGERS *144*

The Application of a Multichannel Chart Recorder to Energy-dispersive Analysis in the Scanning Electron Microscope
R.M. SHARP *149*

A Background Correction for Energy-dispersive X-Ray Analysis of Thin Sections
W.M. SHERRY AND J.B. VAN DER SANDE *154*

Characteristic Isochromats by Photons
M. LINDROOS, G. GRAEFFE AND M. KARRAS *161*

X-Ray Fluorescence Analysis of Catalytic Converters using Single-element Standards and Theoretical Corrections for Interelement Effects
B.E. ARTZ *165*

Calibration Standards
J.R. RHODES *171*

NUMBER 4 OCTOBER 1977

Editorial *175*

A Procedure to Increase Signal in X-Ray Spectrometry
A.McL. MATHIESON *176*

Photographic Recording of the Spatial Distribution of Elements Using an Unmodified, Flat-crystal X-Ray Spectrometer
A. LIVINGSTONE *177*

Matrix Effect Corrections by Ag Kα Compton Scattered Radiation in the Analysis of Rock Samples for Trace Elements
L. LEONI AND M. SAITTA *181*

Mass Thickness Measurement of Pure Element Films by X-Ray Fluorescence Spectroscopy
D. LAGUITTON *187*

X-Ray Emission Intensities of Radionuclides in Fallout from Nuclear Explosions
S.K. SETHI AND B.S. NEGI *192*

Precision of a Commercial, Wavelength-dispersive X-Ray Fluorescence Spectrometer. A Case Study
C. PUPP *196*

Experimental Spectral Distribution versus Kramers' Law for Quantitative X-Ray Fluorescence by the Fundamental Parameters Method
D. LAGUITTON AND W. PARRISH *201*

Total X-Ray Fluorescence Analysis of Geological Samples Using a Low-dilution Lithium Metaborate Fusion Method. Matrix Corrections for Major Elements
M.T. HAUKKA AND I.L. THOMAS *204*

The Calculation of Mylar Film Absorption Correction Coefficients in X-Ray Spectrochemical Analysis of Aqueous Samples
J.G. DICK, C.C. WAN AND R. DiFRUSCIA *212*

Analysis of Plant Material by X-Ray Fluorescence Spectrometry
A. MUDROCH AND O. MUDROCH *215*

Calibration Standards *218*

Letters to the Editor *223*

Author Index to Volume 6

Artz, B.E. *165*
Badica, T. *90*
Barbier, Y. *112*
Bougault, H. *66*
Butt, C.R.M. *144*
Cambon, P. *66*
Ciortea, C. *90*
Crumpton, D. *140*
Denee, P.B. *21*
Dick, J.G. *212*
DiFruscia, R. *212*
Dima, S. *90*
Ebel, H. *30*
Elad, E. *21*
Evans, K.D. *132*
Faulkner, R.G. *73*
Francois, P.E. *140*
Fregerslev, S. *89*
Gedcke, D.A. *21*
Giorgetta, N.E. *2*
Girard, C. *112*
Graeffe, G. *161*
Hall, S.H. *86*
Harbison, L.E. *86*
Haukka, M.T. *204*
Hinchliffe, P. *83*
Hooton, D.H. *2*
Hopkins, A.G. *140*
Hopkins, T.C. *73*
Hutton, J.T. *6, 12*
Karras, M. *161*
Kerrigan, G.C. *83*
Kramer, J. *30*
Laguitton, D. *187, 201*
Leigh, B. *132*
Leoni, L. *181*
Lewis, M. *132*
Lindroos, M. *161*
Livingstone, A. *177*
Mathieson, A.McL. *176*
Mudroch, A. *215*
Mudroch, O. *215*
Neacşu, V. *90*
Negi, B.S. *192*
Norrgård, K. *73*
Norrish, K. *6, 12*
O'Connor, B.H. *83*
Parrish, W. *201*
Pehlivanian, E. *112*
Petrovici, A. *90*
Popescu, I. *90*
Pupp, C. *196*
Puumalainen, P. *80*
Rashiduzzaman Khan, Md. *140*
Riddle, C. *18*
Russ, J.C. *37, 56*
Saitta, M. *181*
Sethi, S.K. *192*
Sharp, R.M. *149*
Shen, R.B. *56*
Sherry, W.M. *154*
Smith, T.E. *18*
Statham, P.J. *94*
Tertian, R. *123*
Thomas, I.L. *204*
Toulhoat, H. *66*
Tschimarov, F. *30*
Urch, D.S. *64*
Vander Sande, J.B. *154*
Verdurmen, E.A.Th. *117*
Vié le Sage, R. *123*
Vigers, R.B.W. *144*
Wan, C.C. *212*
Webber, S. *64*

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